

Date Created : 2008/06/24
Date Issued On : 2008/07/21
PCN# : Q2082601

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Implementation of change:
Expected 1st Device Shipment Date: 2008/10/24

Earliest Year/Work Week of Changed Product: 0843

Change Type Description: Alternate Fab Location

Description of Change (From): Optoelectronics detector devices currently fabrication at China Resources Semiconductor.

Description of Change (To): Optoelectronics detector devices will also be fabricated at the Fairchild Semiconductor 6" fabrication facility located in South Portland, Maine. The South Portland die will be an alternate source to the detector die currently used in the effected FSID list. Product using die from the alternate source will be fully compliant to all published databook specifications and will be interchangeable with the existing product. Quality and reliability will remain at the highest level already demonstrated with Fairchild existing products.

Reason for Change : Establish an additional die source to enhance manufacturing flexibility

Qual/REL Plan Numbers : Q20080303

Qualification :

Passed

Results/Discussion for Qual Plan Number Q20080303

Test: (Autoclave)			
Lot	Device	96-HOURS	Failure Code
Q20080303AAACLVA	H11L1M	0/45	
Q20080303ABACLVA	H11L1M	0/45	
Q20080303ACACLVA	H11L1M	0/45	

Test: (High Humidity, High Temp, Rev. Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080303AAH3TRBA	H11L1M	0/45			
			0/45		
				0/45	
Q20080303ABH3TRBA		0/45			
			0/45		
				0/45	
Q20080303ACH3TRBA		0/45			
			0/45		
				0/45	

Test: (High Temperature Op Life)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080303AAHTOLA		0/45			
			0/45		
				0/45	
Q20080303ABHTOLA		0/45			
			0/45		
				0/45	
Q20080303ACHTOLA		0/45			
			0/45		
				0/45	

Test: (High Temperature Reverse Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080303AAHTRBA		0/45			
			0/45		
				0/45	
Q20080303ABHTRBA		0/45			
			0/45		
				0/45	
Q20080303ACHTRBA		0/45			
			0/45		
				0/45	

Test: (High Temperature Storage Life)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080303AAHTSLA		0/45			
			0/45		
				0/45	
Q20080303ABHTSLA		0/45			
			0/45		
				0/45	
Q20080303ACHTSLA		0/45			
			0/45		
				0/45	

Test: (Low Temperature Storage)					
Lot	Device	168-HOURS	500-HOURS	1000	Failure Code
Q20080303AALTSA		0/45			
			0/45		
				0/45	
Q20080303ABL TSA		0/45			
			0/45		
				0/45	
Q20080303ACL TSA		0/45			
			0/45		
				0/45	

Test: (Power Cycle)					
Lot	Device	5000-CYCLES	10000-CYCLES	15000-CYCLES	Failure Code
Q20080303AAPRCLA		0/45			
			0/45		
				0/45	
Q20080303ABPRCLA		0/45			
			0/45		
				0/45	
Q20080303ACPRCLA		0/45			
			0/45		

				0/45	
Test: (Temperature Humidity Biased Test)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080303AATHBTA		0/45			
			0/45		
				0/45	
Q20080303ABTHBTA		0/45			
			0/45		
				0/45	
Q20080303ACTHBTA		0/45			
			0/45		
				0/45	
Test: -40C, 125C (Temperature Cycle)					
Lot	Device	100-CYCLES	200-CYCLES		Failure Code
Q20080303AATMCL2A	H11L1M	0/45			
Q20080303AATMCL2A	H11L1M		0/45		
Q20080303ABTMCL2A	H11L1M	0/45			
Q20080303ABTMCL2A	H11L1M		0/45		
Q20080303ACTMCL2A	H11L1M	0/45			
Q20080303ACTMCL2A	H11L1M		0/45		
Test: MSL(1), PKG(OPTO-white), PeakTemp(260c), Cycles(3) (Precondition)					
Lot	Device	Results			Failure Code
Q20080303AAPCOPTO1BA	H11L1M	0/180			
Q20080303ABPCOPTO1BA	H11L1M	0/180			
Q20080303ACPCOPTO1BA	H11L1M	0/180			

Product Id Description :

Affected FSIDs :

KAR00035	KAR00052	KAR00054
KAR00055A	KAR00055A_NL	KAR00056
KAR00060A	KAR00061A	KAT00073B
KAT00073	KAT00124	KOI00003A
KOI00003	QCK5TR	QCK5
QRB1113	QRB1114	QRB1133
QRB1134	QRD1113	QRD1114
QRD1114_0191K	QRE00034	QSC112CC6R0
QSC112	QSC112_0056K	QSC112_0212
QSC113C6R0	QSC113	QSC113_0040D
QSC114C	QSC114	QSE113E3R0
QSE113	QSE113_0203	QSE114E3R0
QSE114	QSE114_0219	QSE213C
QSE213	QSE214C	QSE214
QVE00034	QVE00034_0203	QVE00039
QVE11233		